

DETAILED ACTION

1. **Claim(s) 3, 5, 6, 13, 15, 16, 23-26, 29 and 30** have been cancelled by the applicant.

Allowable Subject Matter

2. **Claim(s) 1, 11, 21 and 27** are allowed.
3. The following is an examiner's statement of reasons for allowance: the pertinent prior art of record does not teach or suggest, in combination with the rest of the claim limitations, a method for programming a one time programmable memory, comprising: "wherein said altered characteristic is a change in a threshold voltage of said at least one of said transistors; and detecting said programmed at least one of said transistors by sensing said change in said threshold voltage of said at least one of said transistors; wherein said detecting step comprises the steps of (i) raising a source terminal for each of said array of transistors to a positive potential, (ii) raising a gate terminal for all transistors along a selected row to a positive potential and (iii) detecting whether a drain voltage changes from a precharge voltage level to approximately a cell transistor threshold voltage below said positive gate terminal potential," in regard to **claim 1**; the pertinent prior art of record does not teach or suggest, in combination with the rest of the claim limitations, a one time programmable memory, comprising: "wherein said altered characteristic is a change in a threshold voltage of said at least one of said transistors; and a circuit for sensing said altered characteristic of said at least one of said transistor, wherein said circuit senses said change in said threshold voltage of said at least one of said transistors, and wherein said circuit (i) raises a source terminal for

each of said array of transistors to a positive potential, (ii) raises a gate terminal for all transistors along a selected row to a positive potential and (iii) detects whether a drain voltage changes from a precharge voltage level to approximately a cell transistor threshold voltage below said positive gate potential," in regard to **claim 11**; the pertinent prior art of record does not teach or suggest, in combination with the rest of the claim limitations, a one time programmable memory, or an integrated circuit, comprising: "wherein said altered transistor characteristic is a change in a threshold voltage of said at least one transistor; and a circuit for sensing said altered characteristic of said at least one transistor~ wherein said circuit senses said change in said threshold voltage, and wherein said circuit (i) raises a source terminal for said at least one transistor to a positive potential, (ii) raises a gate terminal for said at least one transistor to a positive potential and (iii) detects whether a drain voltage changes from a precharge voltage level to approximately a cell transistor threshold voltage below said positive gate potential," in regard to **claims 21 and 27**.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

4. **Claim(s) 2, 4, 7-10, 12, 14, 17-20, 22, 28 and 31** depend from independent claims 1, 11, 21 and 27 and as such are therefore allowed for at least the same reasons as set forth above.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to FERNANDO N. HIDALGO whose telephone number is (571)270-3306. The examiner can normally be reached on Monday-Friday, 7:30AM-5:00PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Amir Zarabian can be reached on 571-272-1852. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Art Unit: 2827

/Fernando N. Hidalgo/
Examiner, Art Unit 2827

/Hoai V. Ho/
Primary Examiner, Art Unit 2827